

# APJ14N65F/P/T (AP65R650)

## 650V N-Channel Enhancement Mode MOSFET

### Description

The APJ14N65F/P/T is **CoolFET II** MOSFET family that is utilizing charge balance technology for extremely low on-resistance and low gate charge performance.

APJ14N65F/P/T is suitable for applications which require superior power density and outstanding efficiency

### General Features

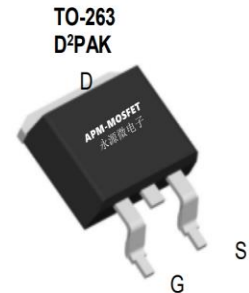
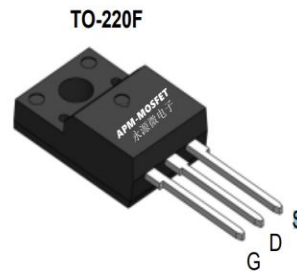
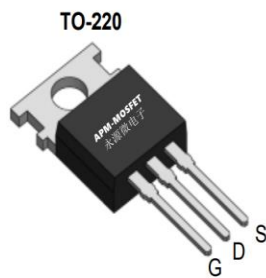
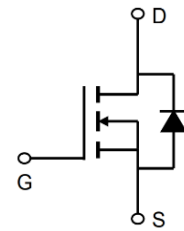
$V_{DS} = 650V$  (Type: 730V)  $IDM = 14A$

$R_{DS(ON)} < 650m\Omega$  @  $V_{GS}=10V$  (Type: 560m $\Omega$ )

### Application

Uninterruptible Power Supply(UPS)

Power Factor Correction (PFC)



### Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
APJ14N65F	TO-220F-3L	AP65R650F XXX YYYY	1000
APJ14N65P	TO-220-3L	AP65R650P XXX YYYY	1000
APJ14N65T	TO-263-3L	AP65R650T XXX YYYY	1000

### Absolute Maximum Ratings ( $T_c=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Value	Unit
$V_{DSS}$	Drain-Source Voltage ( $V_{GS} = 0V$ )	650	V
$I_D$	Continuous Drain Current	8	A
$I_{DM}$	Pulsed Drain Current (note1)	14	A
$V_{GS}$	Gate-Source Voltage	$\pm 30$	V
$E_{AS}$	Single Pulse Avalanche Energy (note2)	125	mJ
$P_D$	Power Dissipation ( $T_c = 25^\circ C$ )	25.5	W
$T_J, T_{stg}$	Operating Junction and Storage Temperature Range	$-55 \sim +150$	$^\circ C$
$R_{thJC}$	Thermal Resistance, Junction-to-Case	4.9	$^\circ C/W$
$R_{thJA}$	Thermal Resistance, Junction-to-Ambient	49	$^\circ C/W$



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### Electrical Characteristics (T<sub>J</sub>=25°C, unless otherwise noted)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
BVDSS	Drain to source breakdown voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250uA	650	700	--	V
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown voltage temperature coefficient	I <sub>D</sub> =250uA, referenced to 25°C	--	0.7	--	V/°C
IDSS	Drain to source leakage current	V <sub>DS</sub> =650V, V <sub>GS</sub> =0V	--	--	1	uA
		V <sub>DS</sub> =520V, T <sub>C</sub> =125°C	--	--	50	uA
IGSS	Gate to source leakage current, forward	V <sub>GS</sub> =30V, V <sub>DS</sub> =0V	--	--	100	nA
	Gate to source leakage current, reverse	V <sub>GS</sub> =-30V, V <sub>DS</sub> =0V	--	--	-100	nA
VGS(TH)	Gate threshold voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250uA	2.5	3.3	4.5	V
RDS(ON)	Drain to source on state resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =3.2A	--	560	650	mΩ
Ciss	Input capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =100V, f=1MHz	--	438	--	pF
Coss	Output capacitance		--	19.5	--	
Crss	Reverse transfer capacitance		--	1.32	--	
td(on)	Turn on delay time	V <sub>DS</sub> =400V, I <sub>D</sub> =3.2A, R <sub>G</sub> =4.7Ω, V <sub>GS</sub> =10V	--	84.8	--	ns
tr	Rising time		--	25.2	--	
td(off)	Turn off delay time		--	227.6	--	
tf	Fall time		--	26.8	--	
Q <sub>g</sub>	Total gate charge	V <sub>DS</sub> =480V, V <sub>GS</sub> =10V, I <sub>D</sub> =3.2A	--	11	--	nC
Q <sub>gs</sub>	Gate-source charge		--	2.1	--	
Q <sub>gd</sub>	Gate-drain charge		--	5.6	--	
IS	Continuous source current	Integral reverse p-n Junction diode in the MOSFET	--	--	11	A
ISM	Pulsed source current		--	--	44	A
VSD	Diode forward voltage drop.	I <sub>S</sub> =3.2A, V <sub>GS</sub> =0V	--	0.7	1.5	V
T <sub>rr</sub>	Reverse recovery time	I <sub>S</sub> =3.2A, V <sub>GS</sub> =0V, V <sub>dd</sub> =400V, di <sub>F</sub> /dt=100A/us,	--	313	--	ns
Q <sub>rr</sub>	Reverse recovery Charge		--	0.877	--	uC

#### Note :

- The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- The EAS data shows Max. rating . L=0.5mH, I<sub>AS</sub> =3.2A, V<sub>DD</sub> =50V, R<sub>G</sub>=25Ω
- The test condition is Pulse Test: I<sub>SD</sub> ≤ I<sub>D</sub>, di/dt = 100A/us, V<sub>DD</sub> ≤ BVDSS, Starting at T<sub>J</sub> =25°C
- The power dissipation is limited by 150°C junction temperature
- The data is theoretically the same as I<sub>D</sub> and I<sub>DM</sub>, in real applications, should be limited by total power dissipation.

### Typical Characteristics

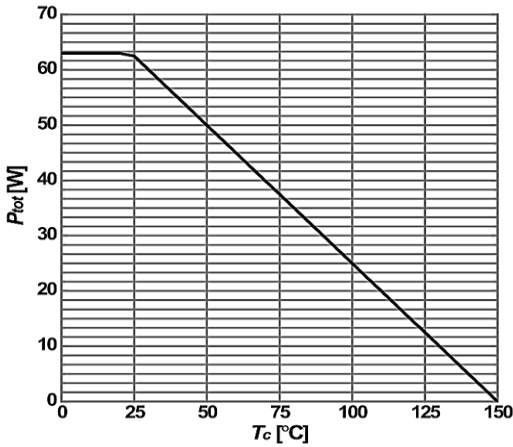


Figure1: Power dissipation (Non FullPAK)

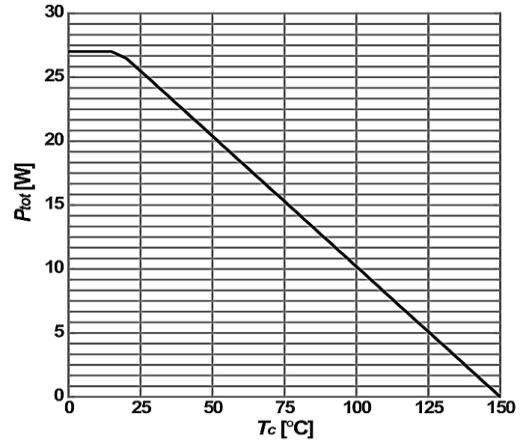


Figure2: Power dissipation (FullPAK)

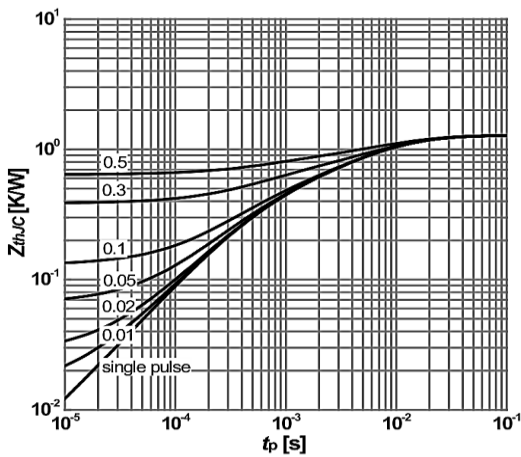


Figure3:Max. transient thermal impedance  
 $Z_{thJC}=f(t_p)$ ; parameter:  $D= t_p/T$

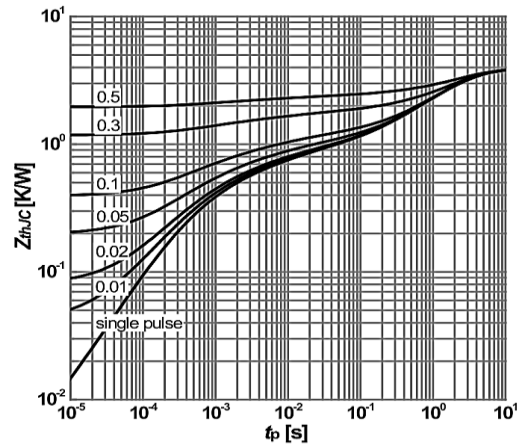


Figure4:Max. transient thermal impedance  
 $Z_{thJC}=f(t_p)$ ; parameter:  $D= t_p/T$

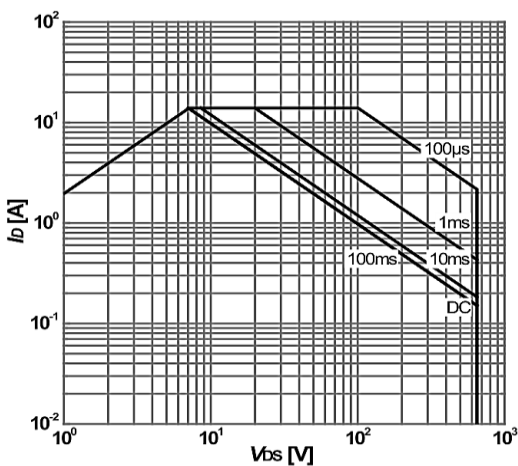


Figure5: Safe operating area (Non FullPAK)  
 $I_D=f(V_{DS})$ ;  $T_J=25^\circ\text{C}$ ;  $D=0$ ; parameter:  $t_p$

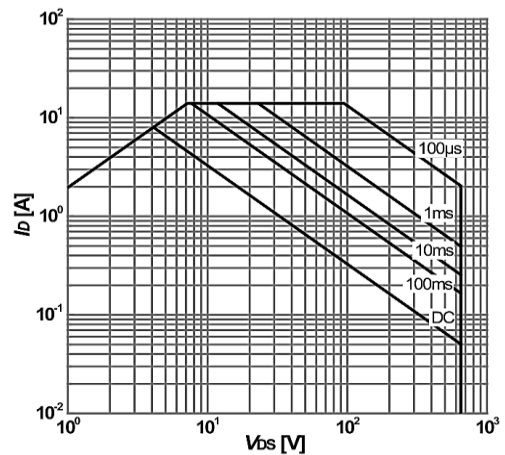
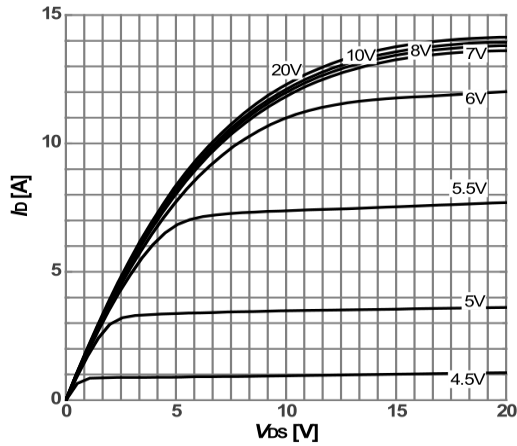


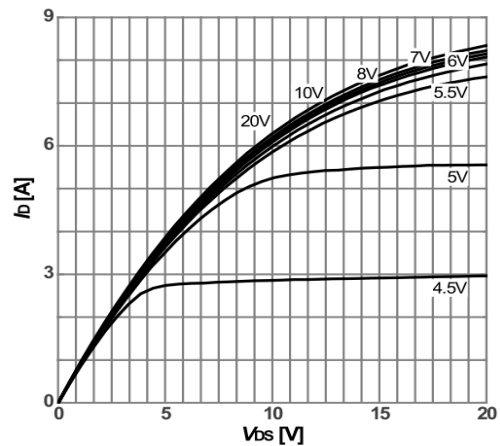
Figure6: Safe operating area (FullPAK)  
 $I_D=f(V_{DS})$ ;  $T_J=25^\circ\text{C}$ ;  $D=0$ ; parameter:  $t_p$

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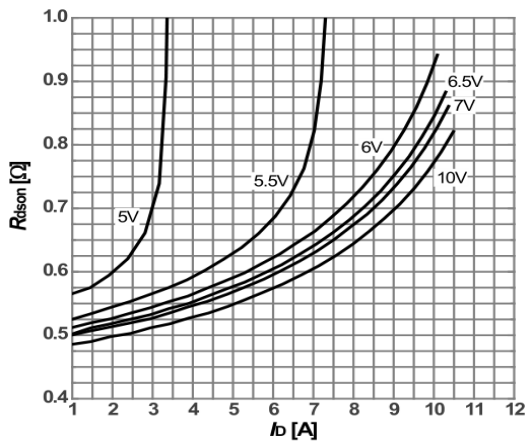
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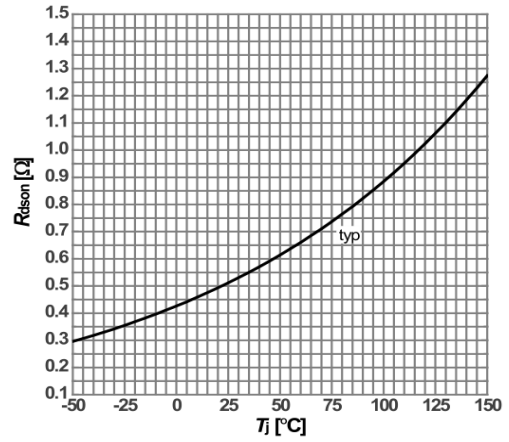
**Figure 7: Typ. output characteristics**  
 $I_D=f(V_{DS}); T_j=25^\circ\text{C};$  parameter:  $V_{GS}$



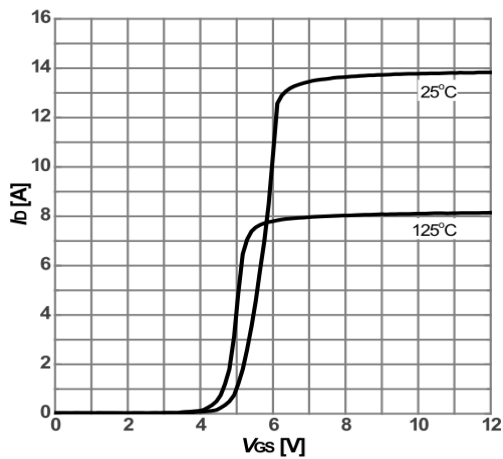
**Figure 8: Typ. output characteristics**  
 $I_D=f(V_{DS}); T_j=125^\circ\text{C};$  parameter:  $V_{GS}$



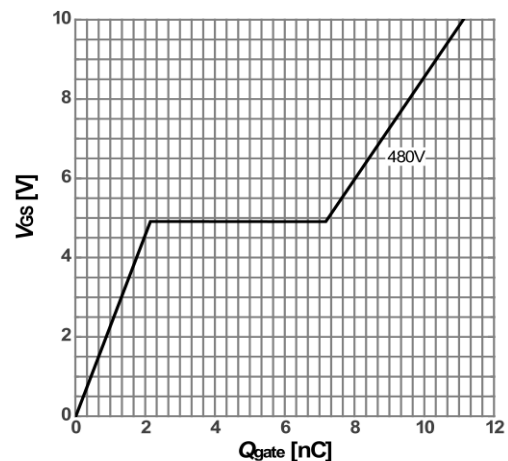
**Figure 9: Typ. drain-source on-state resistance**  
 $R_{DS(on)}=f(I_D); T_j=25^\circ\text{C};$  parameter:  $V_{GS}$



**Figure 10: drain-source on-state resistance**  
 $R_{DS(on)}=f(T_j); I_D=3.2\text{A}; V_{GS}=10\text{V}$



**Figure 11: Type. transfer characteristics**  
 $I_D=f(V_{GS}); V_{DS}=20\text{V};$  parameter:  $T_j$

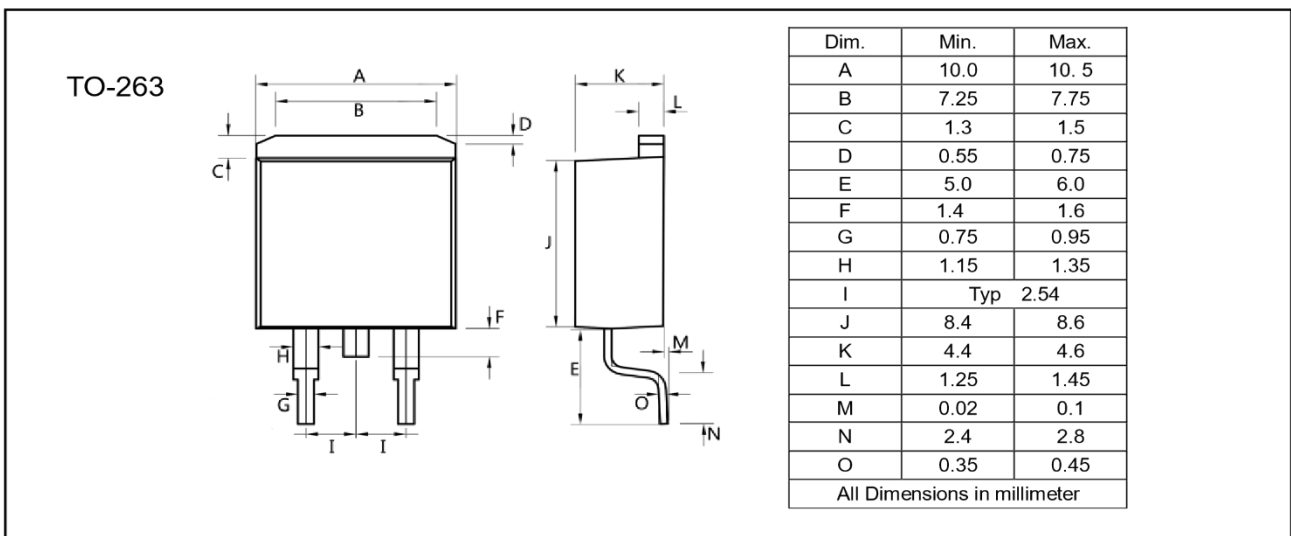
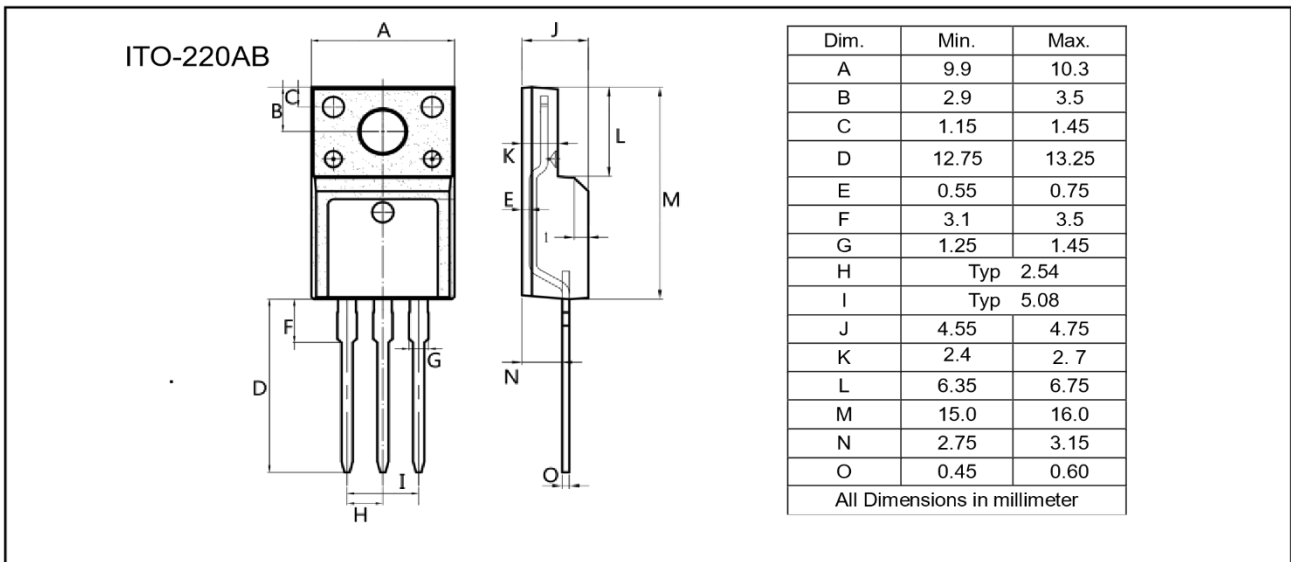
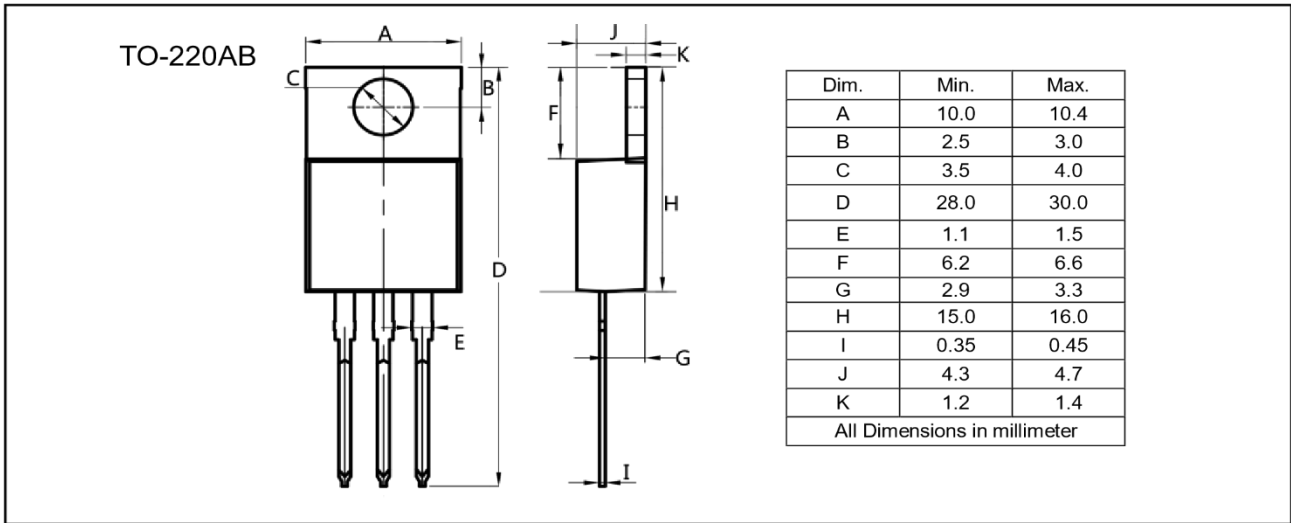


**Figure 12: Type. gate charge**  
 $V_{GS}=f(Q_{gate}); I_D=3.2\text{A pulsed}; V_{DS}=480\text{V}$

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### Package Mechanical Data-TO-X



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<b>Edition</b>	<b>Date</b>	<b>Change</b>
Rve1.0	2018/1/31	Initial release

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